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. 2 1.1.4 The Model Mismatch Problem .

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${f 11}$ Characterisation and modeling of mismatch in MOS transistors for precision analog design

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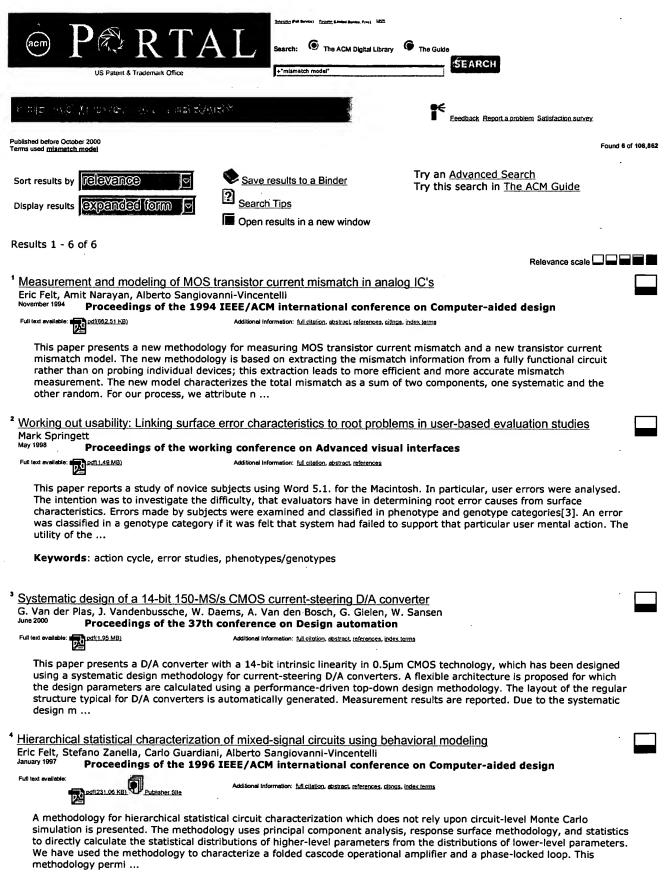
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Keywords: statistical characterization, mixed-signal circuits, behavioral modeling

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Tamal Mukherjee, L. R. Carley, R. A. Rutenbar

Proceedings of the 1994 IEEE/ACM international conference on Computer-aided design

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We describe a synthesis system that takes operating range constraints and inter- and intra-circuit parametric manufacturing variations into account while designing a sized and biased analog circuit. Previous approaches to CAD for analog circuit synthesis have concentrated on nominal analog circuit design, and subsequent optimization of these circuits for statistical fluctuations and operating point ranges. Our approach simultaneously synthesizes and optimizes for operating and manufacturing ...

⁶ Confidence intervals for univariate discrete-event simulation output using the Kalman filter Randall B. Howard, Mark A. Gallagher, Kenneth W. Bauer, Peter S. Maybeck December 1992 Proceedings of the 24th conference on Winter simulation

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